Notice of References Cited Application/Control No. 10/546,620 Examiner Tuan T. Dinh Applicant(s)/Patent Under Reexamination KARIYA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,525,813	04-2009	Kohjiro et al.	361/760
*	В	US-6,014,318	01-2000	Takeda, Shinji	361/764
	U	US-			
	ם	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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	V						
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	х						

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